

# MRS BULLETIN

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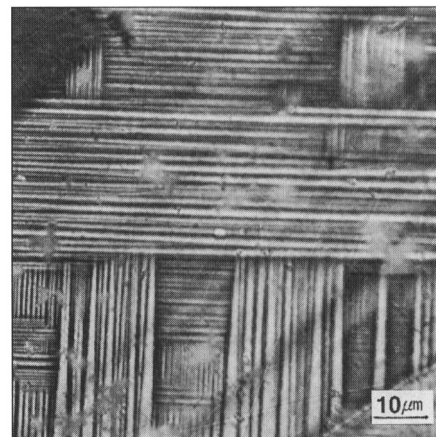
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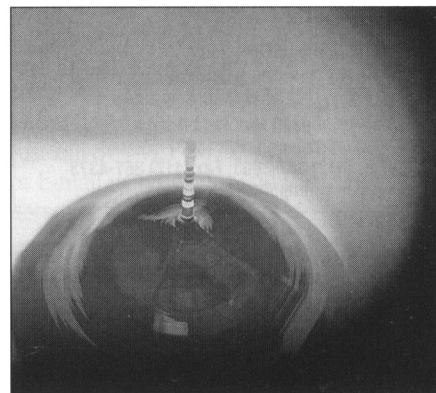
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**ON THE COVER:** Domain configuration of a  $(\text{Na}_{1/2}\text{Bi}_{1/2})\text{TiO}_3$  crystal grown by flux technique at  $350^\circ\text{C}$  (orientation  $\langle 100 \rangle$ , magnification approximately 800 times). Ferroelectric crystals such as these are commonly used in capacitors, transducers, and actuators. Courtesy of Seung-Eek Park for Robert E. Newnham. For more information on this subject, see the article, "Molecular Mechanisms in Smart Materials," by Robert E. Newnham on page 20.

**Inset:** Czochralski-grown crystal being pulled from a polycrystalline silicon melt. The photograph was taken through the viewport window. Courtesy of Mitsubishi Silicon America. Photograph by Ron May, Fort Wayne, Indiana. For more information on the development of semiconductor silicon, see Links of Science & Technology that begins on page 47.



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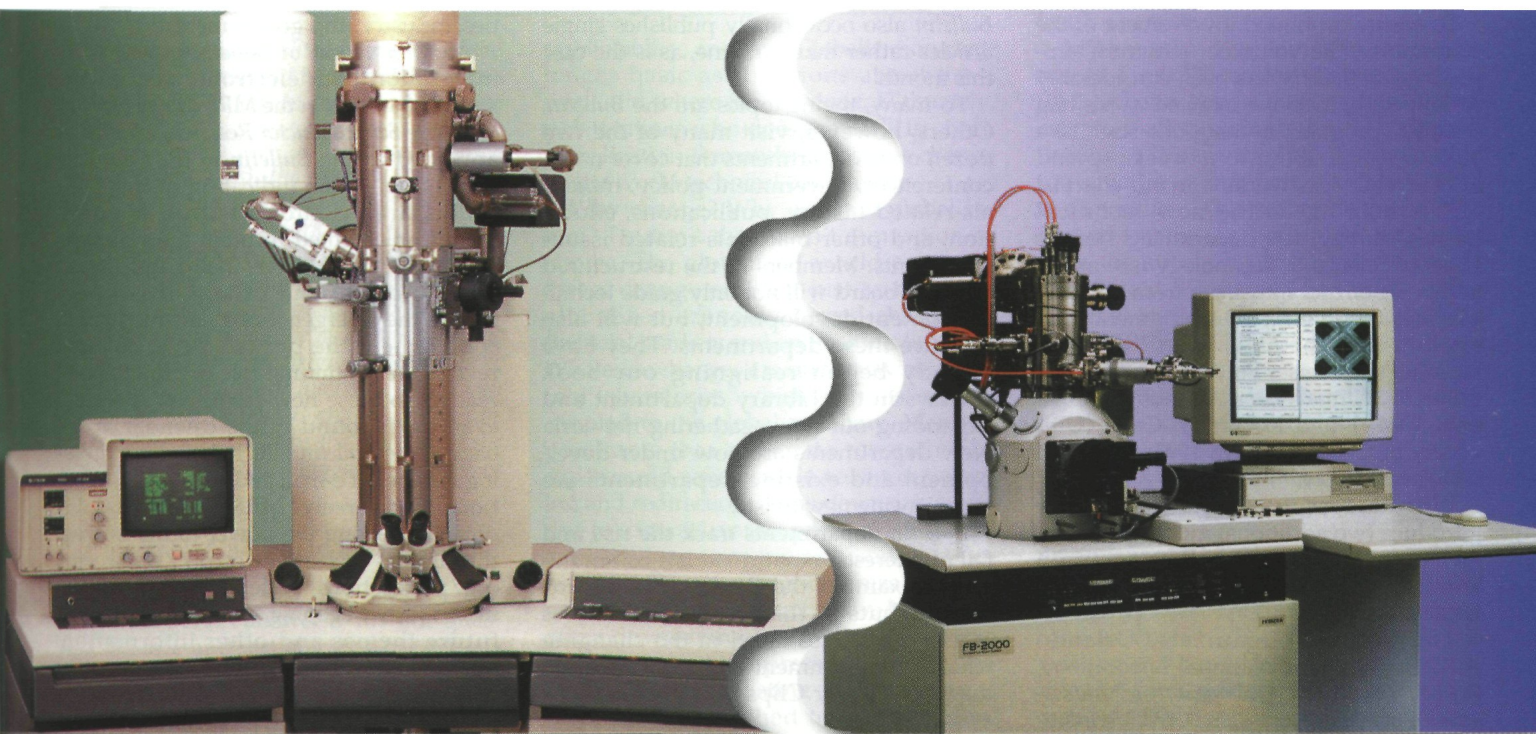
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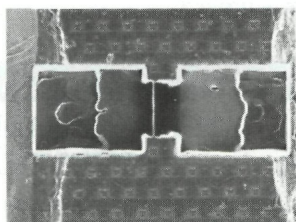
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